

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/710,332	BONALLE ET AL.	
	Examiner	Art Unit	Page 1 of 3
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0233039	11-2004	Beenau et al.	340/005.83
	B	US-2004/0232224	11-2004	Beenau et al.	235/380
	C	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
	D	US-2002/0191816	12-2002	Maritzen et al.	382/115
	E	US-2005/0065872	03-2005	Moebs et al.	705/038
	F	US-5,869,822	02-1999	Meadows et al.	235/380
	G	US-5,987,155	11-1999	Dunn et al.	382/116
	H	US-6,269,348	07-2001	Pare et al.	705/39
	I	US-2001/0053239	12-2001	Takhar, Harinder S.	382/124
	J	US-2002/0062284	05-2002	KAWAN, JOSEPH C.	705/43
	K	US-2002/0095587	07-2002	Doyle et al.	713/186
	L	US-2002/0140542	10-2002	Prokoski et al.	340/5.52
	M	US-2004/0178063	09-2004	Mirchi et al.	204/280

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0149661	08-2003	Mitchell et al.	705/39
	B	US-2003/0226041	12-2003	Palmer et al.	713/202
	C	US-2004/0020982	02-2004	Hoffman et al.	235/379
	D	US-2004/0041690	03-2004	Yamagishi, Junichi	340/005.52
	E	US-2004/0133787	07-2004	Doughty et al.	713/186
	F	US-2005/0001711	01-2005	Doughty et al.	340/005.74
	G	US-2004/0155101	08-2004	Royer et al.	235/379
	H	US-2004/0195314	10-2004	Lee, Ki Deak	235/380
	I	US-2004/0199469	10-2004	Barillova et al.	705/044
	J	US-2004/0208343	10-2004	Golden et al.	382/110
	K	US-2004/0230488	11-2004	Beenau et al.	705/018
	L	US-2004/0232220	11-2004	Beenau et al.	235/380
	M	US-2004/0236701	11-2004	Beenau et al.	705/064

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0239480	12-2004	Beenau et al.	340/005.53
	B	US-2005/0116024	06-2005	Beenau et al.	235/380
	C	US-2005/0005172	01-2005	Haala, Catherine A.	713/202
	D	US-2005/0018658	01-2005	Ikeda et al.	370/352
	E	US-2005/0033992	02-2005	Inabe, Takeshi	713/202
	F	US-2005/0054438	03-2005	Rothschild et al.	463/029
	G	US-2005/0091325	04-2005	Kuwana et al.	709/206
	H	US-2005/0102524	05-2005	Haala, Catherine A.	713/186
	I	US-6,636,620	10-2003	Hoshino, Satoshi	382/124
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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